

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application.

Listing of Claims:

Claims 1-33 (Canceled)

Claim 34 (New): A test head assembly comprising:

 a probe card;
 a contactor; and
 an interposer interconnecting said probe card and said contactor,
 wherein said interposer comprises a first plurality of spring contacts, each of said first plurality of spring contacts comprising a beam extending away from a first surface of said interposer, and
 wherein said beam is contoured to affect a deflection characteristic of said beam.

Claim 35 (New): The test head assembly of claim 34, wherein said beam is contoured along a length of said beam.

Claim 36 (New): The test head assembly of claim 34, wherein said beam is contoured to increase a bending moment of said beam.

Claim 37 (New): The test head assembly of claim 34, wherein said beam is contoured to increase an elastic range of said beam.

Claim 38 (New): The test head assembly of claim 34, wherein said beam is contoured to increase an elastic deflection ratio of said beam.

Claim 39 (New): The test head assembly of claim 34, wherein said beam is contoured to increase an area moment of inertia of said beam.

Claim 40 (New): The test head assembly of claim 34, wherein said beam is contoured to stiffen said beam.

Claim 41 (New): The test head assembly of claim 34, wherein said beam is corrugated.

Claim 42 (New): The test head assembly of claim 34, wherein said beam is contoured along a cross-sectional width thereof.

Claim 43 (New): The test head assembly of claim 42, wherein said cross-sectional width is "V" shaped.

Claim 42 (New): The test head assembly of claim 42, wherein said cross-sectional width is "U" shaped.

Claim 44 (New): The test head assembly of claim 42, wherein said cross-sectional width comprises a rib.

Claim 45 (New): The test head assembly of claim 34, wherein said beam is serpentine shaped.

Claim 46 (New): The test head assembly of claim 34, wherein said interposer further comprises a second plurality of spring contacts, each of said second plurality of spring contacts comprising a contoured beam extending away from a second surface of said interposer.

Claim 47 (New): A test head assembly comprising:

a probe card comprising a plurality of first contact areas;
a contactor comprising a plurality of second contact areas; and
an interposer comprising a plurality of first spring contact structures each contacting one of said first contact areas, and a plurality of second spring contact structures each contacting one of said second contact areas, wherein ones of said first spring contact structures are electrically connected through said interposer to ones of said second spring contact structures,
wherein ones of said first spring contact structures or ones of said second spring contact structures comprise electrically connected pairs of contacts extending away from a surface of said interposer.

Claim 48 (New): The test head assembly of claim 47, wherein ones of both said first spring contact structures and said second spring contact structures comprise electrically connected pairs of contacts extending away from a surface of said interposer.

Claim 49 (New): The test head assembly of claim 47, wherein each of said pairs of contacts comprise opposing curved beams.

Claim 50 (New): The test head assembly of claim 47, wherein each of said pairs of contacts comprise mirror image beams.

Claim 51 (New): A test head assembly comprising:

a probe card;
a contactor; and
a first plurality of spring contacts interconnecting said probe card and said contactor,
wherein each of said first plurality of spring contacts comprises a beam contoured to affect a deflection characteristic of said beam.

Claim 52 (New): The test head assembly of claim 51, wherein said beam is contoured along a length of said beam.

Claim 53 (New): The test head assembly of claim 51, wherein said beam is contoured to increase a bending moment of said beam.

Claim 54 (New): The test head assembly of claim 51, wherein said beam is contoured to increase an elastic range of said beam.

Claim 55 (New): The test head assembly of claim 51, wherein said beam is contoured to increase an elastic deflection ratio of said beam.

Claim 56 (New): The test head assembly of claim 51, wherein said beam is contoured to increase an area moment of inertia of said beam.

Claim 57 (New): The test head assembly of claim 51, wherein said beam is contoured to stiffen said beam.

Claim 58 (New): The test head assembly of claim 51, wherein said beam is corrugated.

Claim 59 (New): The test head assembly of claim 51, wherein said beam is contoured along a cross-sectional width thereof.

Claim 60 (New): The test head assembly of claim 59, wherein said cross-sectional width is "V" shaped.

Claim 61 (New): The test head assembly of claim 59, wherein said cross-sectional width is "U" shaped.

Claim 62 (New): The test head assembly of claim 59, wherein said cross-sectional width comprises a rib.

Claim 63 (New): The test head assembly of claim 51, wherein said beam is serpentine shaped.

Claim 64 (New): The test head assembly of claim 51 further comprising a second plurality of spring contacts disposed on said contactor to contact an electronic device to be tested, wherein each of said second plurality of spring contacts comprising a contoured beam,.

Claim 65 (New): A test head assembly comprising:

- a probe card comprising a plurality of first contact areas;
- a contactor comprising a plurality of device contacts for contacting an electronic device to be tested; and
- a first plurality of pairs of spring contacts, each pair of spring contacts electrically connecting one of said contact areas with one of said device contacts.

Claim 66 (New): The test head assembly of claim 65, wherein each of said device contacts comprises a pair of beams.

Claim 67 (New): The test head assembly of claim 65, wherein each of said pairs of spring contacts comprise opposing curved beams.

Claim 68 (New): The test head assembly of claim 65, wherein each of said pairs of spring contacts comprise mirror image beams.